

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Patent Application of

Victor V. VERBINSKI, et al.

Group Art Unit: 2884

Serial No.: 10/717,632

Examiner: LEE, SHUN K.

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For: **SYSTEM AND METHOD FOR TARGET INSPECTION USING DISCRETE  
PHOTON COUNTING AND NEUTRON DETECTION**

**RESPONSE TO NON-FINAL OFFICE ACTION**

**BY FACSIMILE - 571-273-8300**

Mail Stop Amendment  
Commissioner for Patents  
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Sir:

The following is intended to be fully responsive to the non-final Office Action mailed  
July 5, 2007.